

OptiMOS™ Power-Transistor

Feature

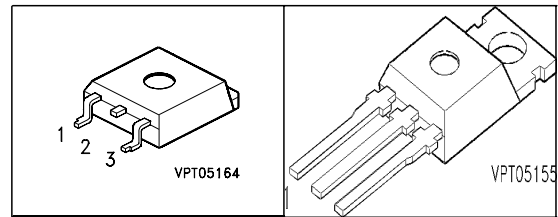
- N-Channel
- Enhancement mode
- Logic Level
- Excellent Gate Charge x $R_{DS(on)}$ product (FOM)
- Superior thermal resistance
- 175°C operating temperature
- Avalanche rated
- dv/dt rated

Product Summary

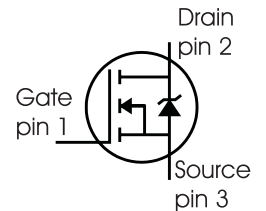
| | | |
|-------------------------------|-----|----|
| V_{DS} | 30 | V |
| $R_{DS(on)}$ max. SMD version | 2.8 | mΩ |
| I_D | 80 | A |

P-TO263-3-2

P-TO220-3-1



| Type | Package | Ordering Code | Marking |
|----------------|-------------|---------------|---------|
| SPP80N03S2L-03 | P-TO220-3-1 | Q67040-S4248 | 2N03L03 |
| SPB80N03S2L-03 | P-TO263-3-2 | Q67040-S4259 | 2N03L03 |



Maximum Ratings, at $T_j = 25\text{ °C}$, unless otherwise specified

| Parameter | Symbol | Value | Unit |
|--|----------------|-------------|-------|
| Continuous drain current $T_C = 25\text{ °C}$, ¹⁾ $T_C = 100\text{ °C}$ | I_D | 80 80 | A |
| Pulsed drain current $T_C = 25\text{ °C}$ | I_D puls | 320 | |
| Avalanche energy, single pulse $I_D = 80\text{ A}$, $V_{DD} = 25\text{ V}$, $R_{GS} = 25\text{ Ω}$ | E_{AS} | 810 | mJ |
| Reverse diode dv/dt $I_S = 80\text{ A}$, $V_{DS} = 24\text{ V}$, $di/dt = 200\text{ A/μs}$, $T_{jmax} = 175\text{ °C}$ | dv/dt | 6 | kV/μs |
| Gate source voltage | V_{GS} | ±20 | V |
| Power dissipation $T_C = 25\text{ °C}$ | P_{tot} | 300 | W |
| Operating and storage temperature | T_j, T_{stg} | -55... +175 | °C |
| IEC climatic category; DIN IEC 68-1 | | 55/175/56 | |

Thermal Characteristics

| Parameter | Symbol | Values | | | Unit |
|---|------------|--------|------|----------|------|
| | | min. | typ. | max. | |
| Characteristics | | | | | |
| Thermal resistance, junction - case | R_{thJC} | - | - | 0.5 | K/W |
| Thermal resistance, junction - ambient, leaded | R_{thJA} | - | - | 62 | |
| SMD version, device on PCB: @ min. footprint @ 6 cm ² cooling area ²⁾ | R_{thJA} | - | - | 62 40 | |

Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Values | | | Unit |
|--|---------------|--------|------------|------------|-----------|
| | | min. | typ. | max. | |
| Static Characteristics | | | | | |
| Drain-source breakdown voltage $V_{GS}=0V, I_D=1mA$ | $V_{(BR)DSS}$ | 30 | - | - | V |
| Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D=250\mu A$ | $V_{GS(th)}$ | 1.2 | 1.6 | 2 | |
| Zero gate voltage drain current $V_{DS}=30V, V_{GS}=0V, T_j=25^\circ C$ $V_{DS}=30V, V_{GS}=0V, T_j=125^\circ C$ | I_{DSS} | - | 0.01 1 | 1 100 | μA |
| Gate-source leakage current $V_{GS}=20V, V_{DS}=0V$ | I_{GSS} | - | 1 | 100 | nA |
| Drain-source on-state resistance $V_{GS}=4.5V, I_D=80A$ $V_{GS}=4.5V, I_D=80A, \text{SMD version}$ | $R_{DS(on)}$ | - | 3.2 2.9 | 3.8 3.5 | $m\Omega$ |
| Drain-source on-state resistance ³⁾ $V_{GS}=10V, I_D=80A$ $V_{GS}=10V, I_D=80A, \text{SMD version}$ | $R_{DS(on)}$ | - | 2.5 2.2 | 3.1 2.8 | |

¹Current limited by bondwire; with a $R_{thJC} = 0.5\text{ K/W}$ the chip is able to carry $I_D = 255A$ and calculated with max. source pin temperature of $85^\circ C$.

²Device on $40mm \times 40mm \times 1.5mm$ epoxy PCB FR4 with 6 cm^2 (one layer, $70\ \mu m$ thick) copper area for drain connection. PCB is vertical without blown air.

³Diagrams are related to straight lead versions

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Values | | | Unit |
|--------------------------------|--------------|---|--------|------|------|----------|
| | | | min. | typ. | max. | |
| Dynamic Characteristics | | | | | | |
| Transconductance | g_{fs} | $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$, $I_D = 80\text{A}$ | 93 | 185 | - | S |
| Input capacitance | C_{iss} | $V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1\text{MHz}$ | - | 6100 | 7600 | pF |
| Output capacitance | C_{oss} | | - | 2360 | 2950 | |
| Reverse transfer capacitance | C_{rss} | | - | 555 | 830 | |
| Gate resistance | R_G | | - | 2.5 | - | Ω |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD} = 15\text{V}$, $V_{GS} = 10\text{V}$, $I_D = 40\text{A}$, $R_G = 1.1\Omega$ | - | 11.8 | 17.7 | ns |
| Rise time | t_r | | - | 105 | 158 | |
| Turn-off delay time | $t_{d(off)}$ | | - | 99 | 148 | |
| Fall time | t_f | | - | 90 | 135 | |

Gate Charge Characteristics

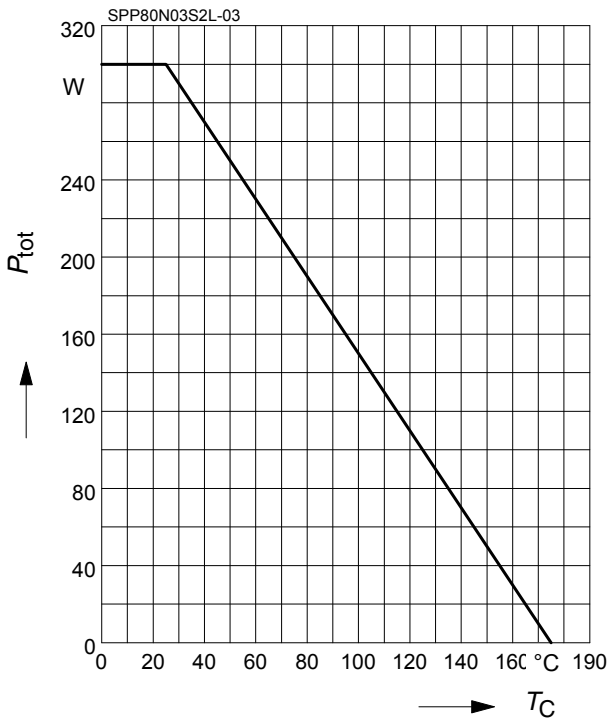
| | | | | | | |
|-----------------------|-----------------|--|---|-----|-----|----|
| Gate to source charge | Q_{gs} | $V_{DD} = 24\text{V}$, $I_D = 80\text{A}$ | - | 18 | 23 | nC |
| Gate to drain charge | Q_{gd} | | - | 51 | 75 | |
| Gate charge total | Q_g | $V_{DD} = 24\text{V}$, $I_D = 80\text{A}$, $V_{GS} = 0$ to 10V | - | 160 | 210 | |
| Gate plateau voltage | $V_{(plateau)}$ | $V_{DD} = 24\text{V}$, $I_D = 80\text{A}$ | - | 2.9 | - | V |

Reverse Diode

| | | | | | | |
|--|----------|---|---|----|-----|----|
| Inverse diode continuous forward current | I_S | $T_C = 25^\circ\text{C}$ | - | - | 80 | A |
| Inverse diode direct current, pulsed | I_{SM} | | - | - | 320 | |
| Inverse diode forward voltage | V_{SD} | $V_{GS} = 0\text{V}$, $f = 80\text{A}$ | - | 1 | 1.3 | V |
| Reverse recovery time | t_{rr} | $V_R = 15\text{V}$, $f = I_S$, $di_f/dt = 100\text{A}/\mu\text{s}$ | - | 58 | 72 | ns |
| Reverse recovery charge | Q_{rr} | | - | 71 | 88 | nC |

1 Power dissipation

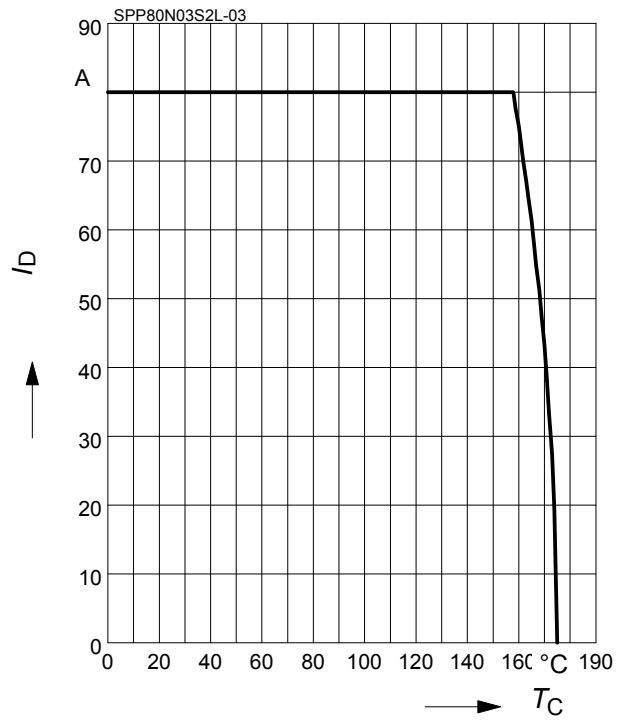
$$P_{tot} = f(T_C)$$



2 Drain current

$$I_D = f(T_C)$$

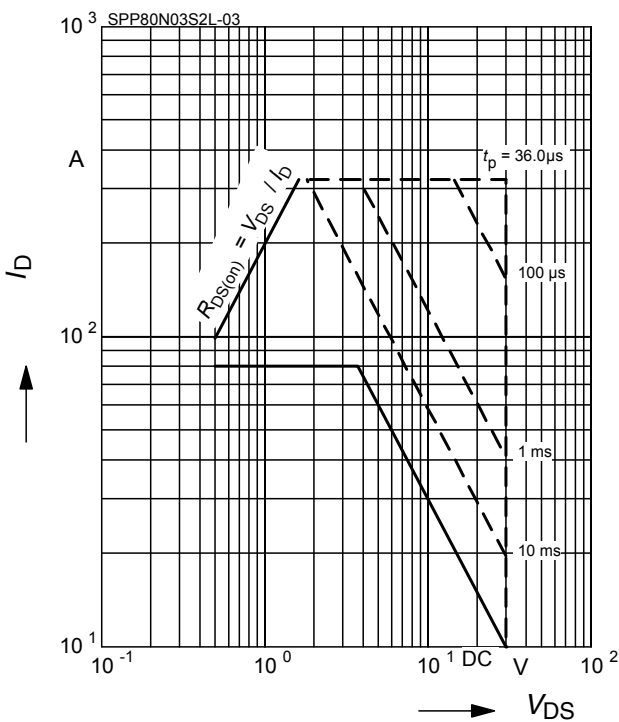
parameter: $V_{GS} \geq 10\text{ V}$



3 Safe operating area

$$I_D = f(V_{DS})$$

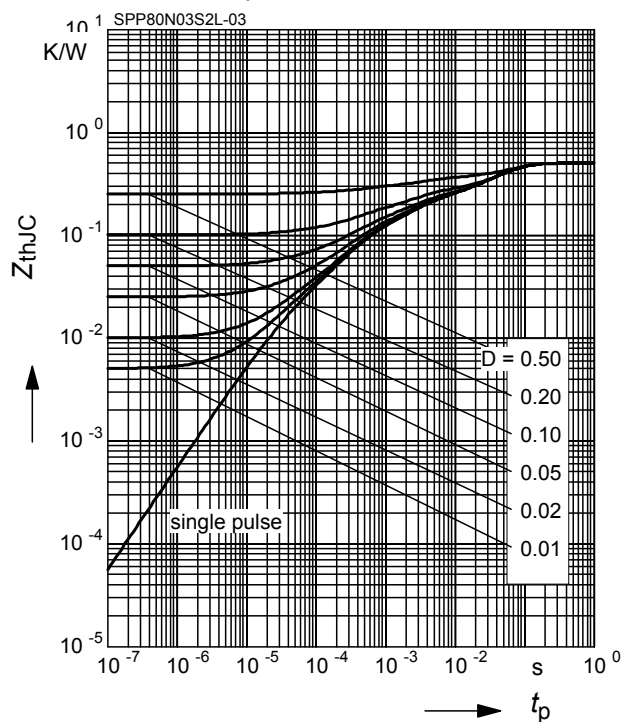
parameter: $D = 0$, $T_C = 25\text{ °C}$



4 Transient thermal impedance

$$Z_{thJC} = f(t_p)$$

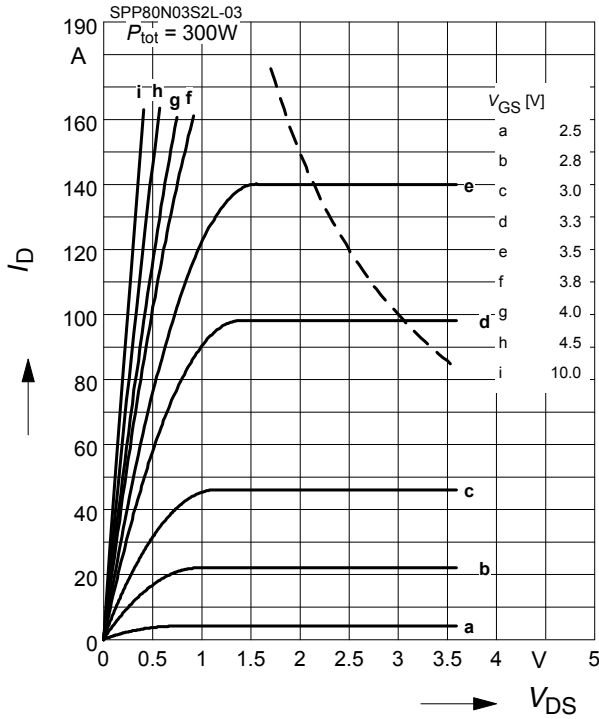
parameter: $D = t_p/T$



5 Typ. output characteristic

$I_D = f(V_{DS}); T_j = 25^\circ\text{C}$

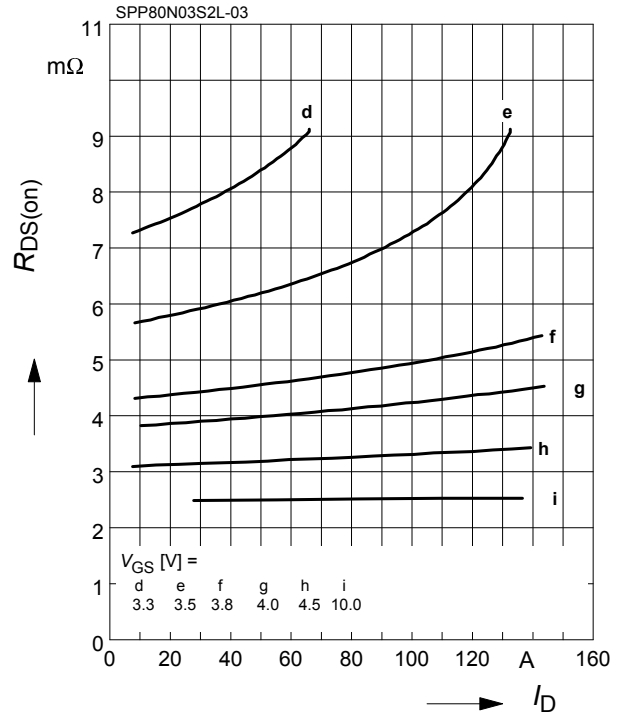
parameter: $t_p = 80 \mu\text{s}$



6 Typ. drain-source on resistance

$R_{DS(on)} = f(I_D)$

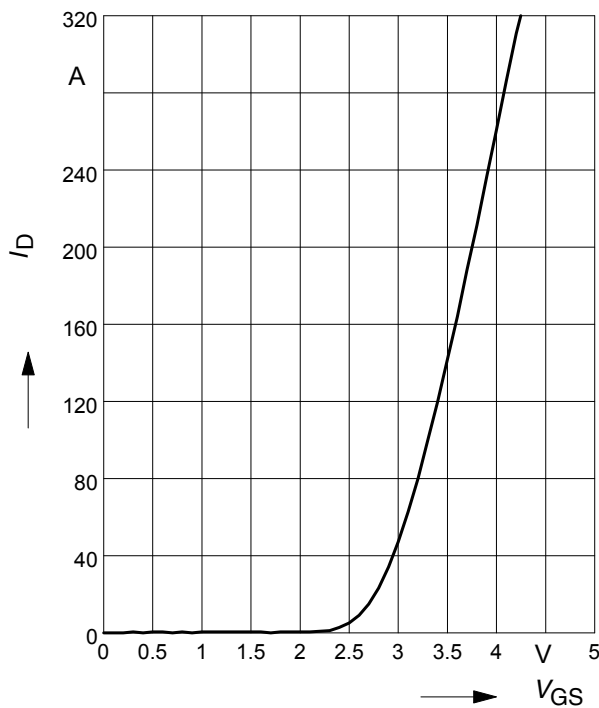
parameter: V_{GS}



7 Typ. transfer characteristics

$I_D = f(V_{GS}); V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$

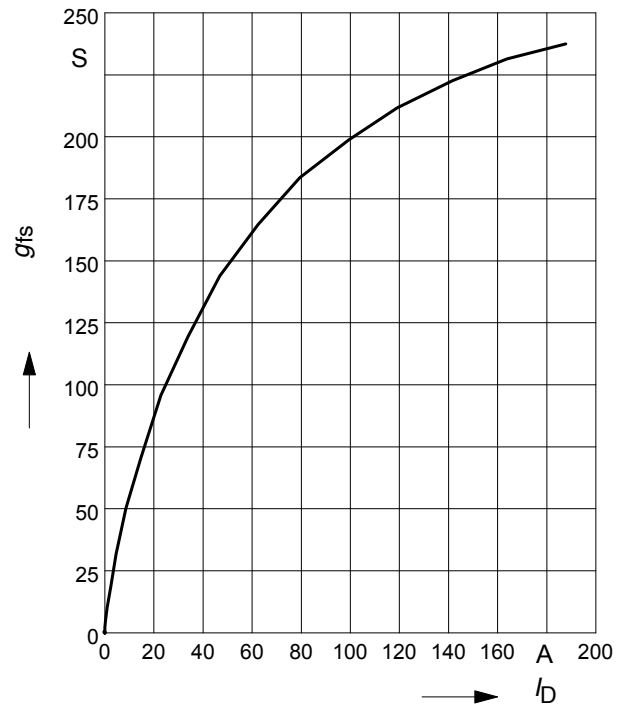
parameter: $t_p = 80 \mu\text{s}$



8 Typ. forward transconductance

$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$

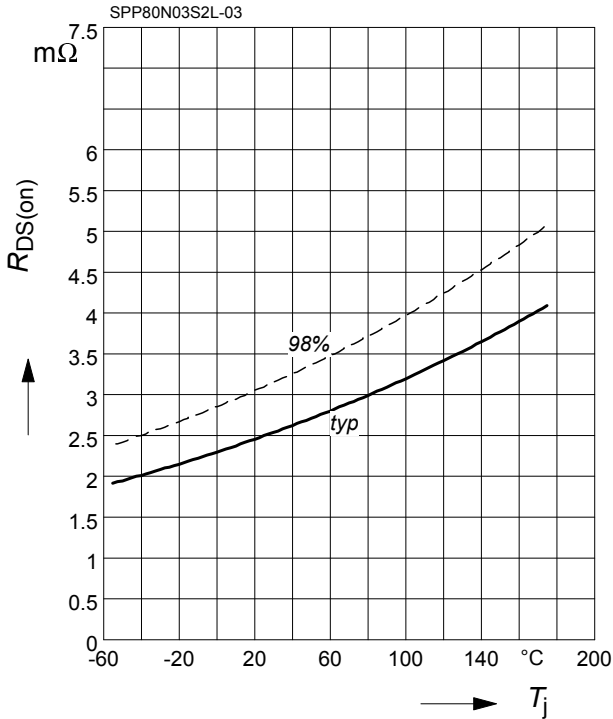
parameter: g_{fs}



9 Drain-source on-state resistance

$$R_{DS(on)} = f(T_j)$$

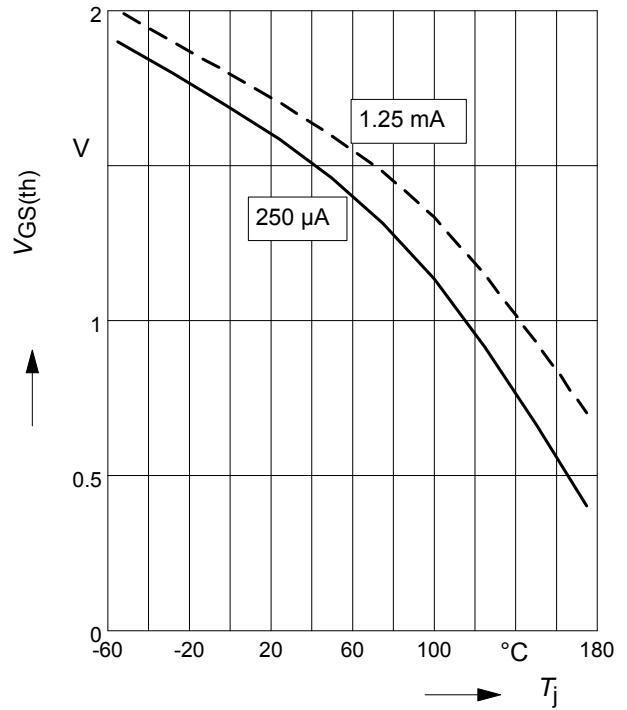
parameter : $I_D = 80 \text{ A}$, $V_{GS} = 10 \text{ V}$



10 Typ. gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

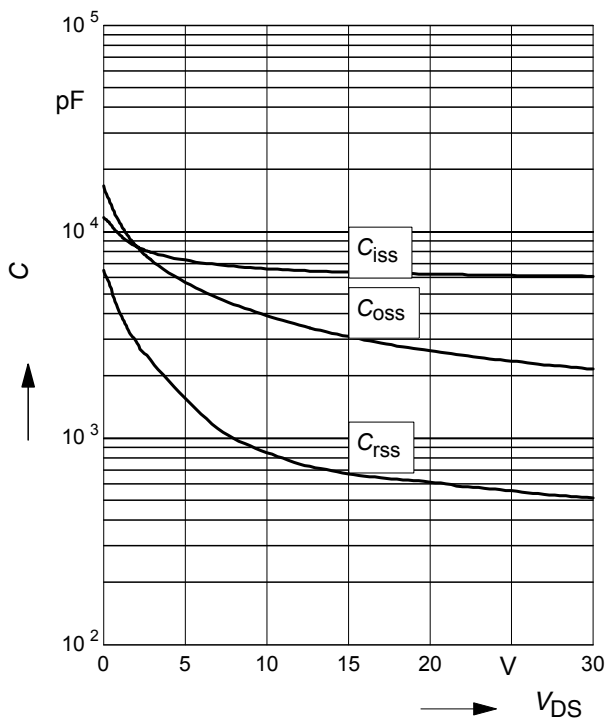
parameter: $V_{GS} = V_{DS}$



11 Typ. capacitances

$$C = f(V_{DS})$$

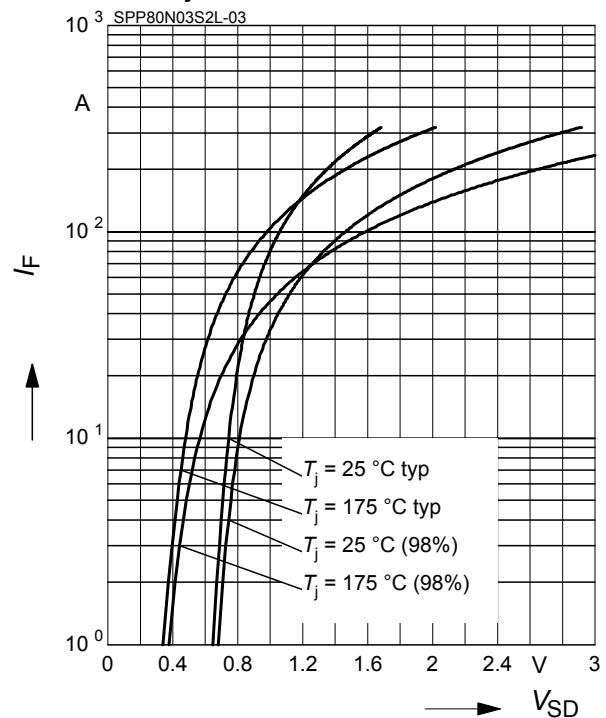
parameter: $V_{GS}=0\text{V}$, $f=1 \text{ MHz}$



12 Forward character. of reverse diode

$$I_F = f(V_{SD})$$

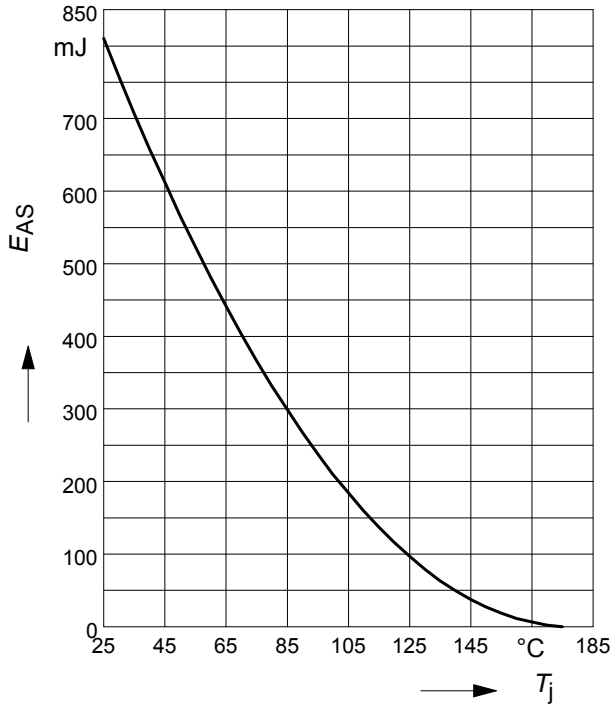
parameter: T_j , $t_p = 80 \mu\text{s}$



13 Typ. avalanche energy

$$E_{AS} = f(T_j)$$

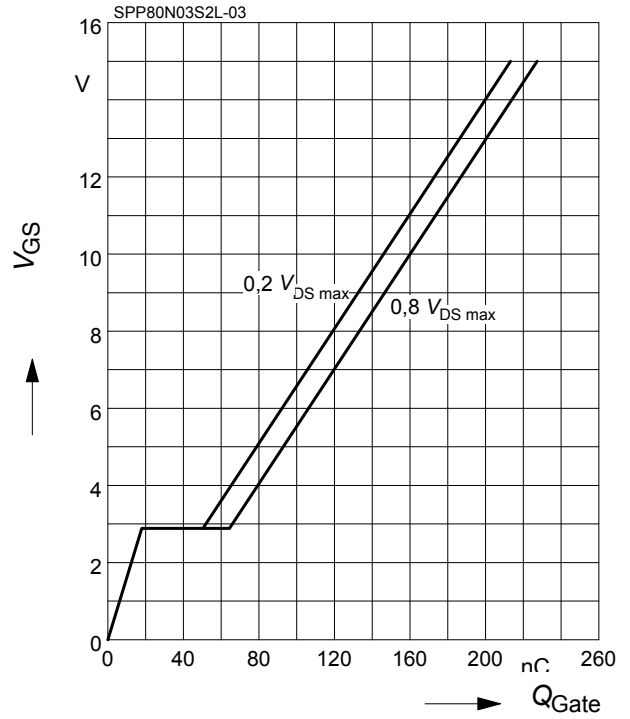
par.: $I_D = 80 \text{ A}$, $V_{DD} = 25 \text{ V}$, $R_{GS} = 25 \Omega$



14 Typ. gate charge

$$V_{GS} = f(Q_{Gate})$$

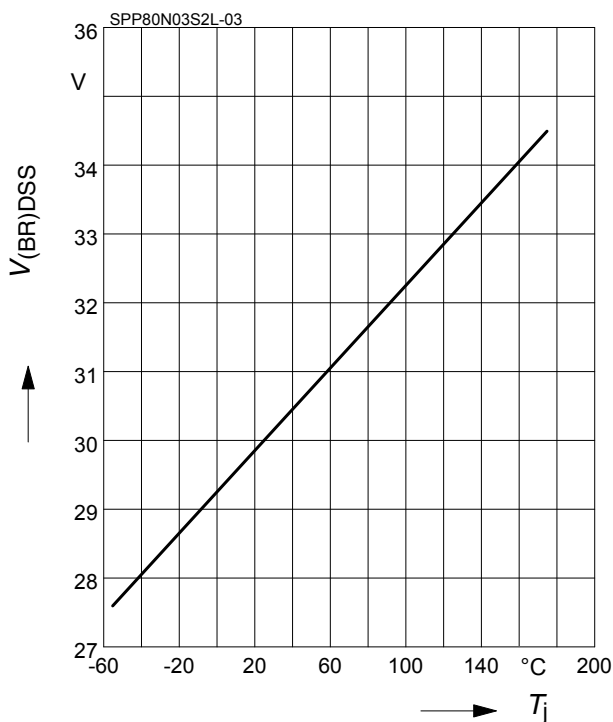
parameter: $I_D = 80 \text{ A}$ pulsed



15 Drain-source breakdown voltage

$$V_{(BR)DSS} = f(T_j)$$

parameter: $I_D = 10 \text{ mA}$



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